Power LDMOS transistor

Rev. 2 — 12 July 2013

Product data sheet

1. Product profile

1.1 General description

150 W LDMOS power transistor for base station applications at frequencies from 2500 MHz to 2700 MHz.

Table 1. Typical performance

Typical RF performance at $T_{case} = 25 \ ^{\circ}C$ in a common source class-AB production test circuit.

Mode of operation	f	I _{Dq}	V_{DS}	$P_{L(AV)}$	Gp	η_D	ACPR _{885k}	ACPR _{5M}
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)	(dBc)
IS-95	2500 to 2700	1200	28	30	16.5	26	-47 <mark>11</mark>	-
Single carrier W-CDMA	2500 to 2700	1200	28	45	16.5	31	-	-38[2]

 Single carrier IS-95 with pilot, paging, sync and 6 traffic channels (Walsh codes 8 - 13). PAR = 9.7 dB at 0.01 % probability on the CCDF. Channel bandwidth is 1.2288 MHz.

[2] 3GPP; test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF. Channel bandwidth is 3.84 MHz.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Designed for broadband operation (2500 MHz to 2700 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

 RF power amplifiers for base stations and multi carrier applications in the 2500 MHz to 2700 MHz frequency range



Power LDMOS transistor

2. Pinning information

5 source [1]	Pin	Description		Simplified outline	Graphic symbol
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	BLF7G2	7L-150P (SOT539A)			
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	1	drain1			
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	2	drain2			
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	3	gate1		5	
BLF7G27LS-150P (SOT539B) $1 drain1 2 drain2 3 gate1 4 gate2 1 drain4 drain5 $	4	gate2		3 4	35
sym117 BLF7G27LS-150P (SOT539B) 1 drain1 2 drain2 3 gate1 4 gate2	5	source	<u>[1]</u>		
BLF7G27LS-150P (SOT539B)1drain12drain23gate14gate2					'H
1 drain1 2 drain2 3 gate1 4 gate2 1^2 3^4 3^4 3^4 4^4 4^4 4^4 3^4 3^4 4^4 3^4 4^4 3^4 4^4 3^4 4^4 3^4 3^4 3^4 4^4 3^4					
$\begin{array}{cccc} 2 & drain2 \\ 3 & gate1 \\ 4 & gate2 \\ \end{array}$	DI EZCO				2 sym117
$\begin{array}{cccccccccccccccccccccccccccccccccccc$					
$\begin{array}{cccccccccccccccccccccccccccccccccccc$					
4 gate2 3 4 4 5	1	drain1			
5 source [1]	1 2	drain1 drain2			sym117
	1 2 3	drain1 drain2 gate1		5	sym117

[1] Connected to flange.

3. Ordering information

Table 3.Ordering information

Type number	Package					
	Name	Description	Version			
BLF7G27L-150P	-	flanged balanced LDMOST ceramic package; 2 mounting holes; 4 leads	SOT539A			
BLF7G27LS-150P	-	earless flanged balanced LDMOST ceramic package; 4 leads	SOT539B			

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage		-	65	V
V _{GS}	gate-source voltage		-0.5	+13	V
I _D	drain current		-	37	А
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	225	°C

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5. Thermal characteristics

Table 5.	Thermal characteristics			
Symbol	Parameter	Conditions	Тур	Unit
R _{th(j-c)}	thermal resistance from junction to case	$T_{case} = 80 \ ^{\circ}C; P_{L} = 30 \ W$	0.25	K/W

6. Characteristics

Table 6. C	haracteristics
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 $T_i = 25 \ ^{\circ}C$ unless otherwise specified.

Parameter	Conditions	Min	Тур	Max	Unit
drain-source breakdown voltage	V_{GS} = 0 V; I_D = 1 mA	65	-	-	V
gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 100 \text{ mA}$	1.3	1.9	2.3	V
drain leakage current	V_{GS} = 0 V; V_{DS} = 28 V	-	-	5	μA
drain cut-off current	$\label{eq:VGS} \begin{array}{l} V_{GS} = V_{GS(th)} + 3.75 \text{ V}; \\ V_{DS} = 10 \text{ V} \end{array}$	16.75	19	-	A
gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	500	nA
forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 3.57 \text{ A}$	-	0.86	-	S
drain-source on-state resistance	$\label{eq:VGS} \begin{array}{l} V_{GS} = V_{GS(th)} + 3.75 \text{ V}; \\ I_D = 3.5 \text{ A} \end{array}$	-	0.14	-	Ω
	drain-source breakdown voltage gate-source threshold voltage drain leakage current drain cut-off current gate leakage current forward transconductance	$ \begin{array}{ll} \mbox{drain-source breakdown voltage} & V_{GS} = 0 \ V; \ I_D = 1 \ mA \\ \mbox{gate-source threshold voltage} & V_{DS} = 10 \ V; \ I_D = 100 \ mA \\ \mbox{drain leakage current} & V_{GS} = 0 \ V; \ V_{DS} = 28 \ V \\ \mbox{drain cut-off current} & V_{GS} = V_{GS(th)} + 3.75 \ V; \\ \ V_{DS} = 10 \ V \\ \mbox{gate leakage current} & V_{GS} = 11 \ V; \ V_{DS} = 0 \ V \\ \mbox{forward transconductance} & V_{DS} = 10 \ V; \ I_D = 3.57 \ A \\ \mbox{drain-source on-state resistance} & V_{GS} = V_{GS(th)} + 3.75 \ V; \\ \end{array} $	$ \begin{array}{ll} \mbox{drain-source breakdown voltage} & V_{GS} = 0 \ V; \ I_D = 1 \ mA & 65 \\ \mbox{gate-source threshold voltage} & V_{DS} = 10 \ V; \ I_D = 100 \ mA & 1.3 \\ \mbox{drain leakage current} & V_{GS} = 0 \ V; \ V_{DS} = 28 \ V & - \\ \mbox{drain cut-off current} & V_{GS} = V_{GS(th)} + 3.75 \ V; \\ \mbox{drain cut-off current} & V_{GS} = 11 \ V; \ V_{DS} = 0 \ V & - \\ \mbox{gate leakage current} & V_{DS} = 10 \ V; \ I_D = 3.57 \ A & - \\ \mbox{drain-source on-state resistance} & V_{GS} = V_{GS(th)} + 3.75 \ V; & - \\ \end{array} $	$ \begin{array}{llllllllllllllllllllllllllllllllllll$	$ \begin{array}{cccc} drain-source breakdown voltage & V_{GS} = 0 \ V; \ I_D = 1 \ mA & 65 & - & - \\ gate-source threshold voltage & V_{DS} = 10 \ V; \ I_D = 100 \ mA & 1.3 & 1.9 & 2.3 \\ drain leakage current & V_{GS} = 0 \ V; \ V_{DS} = 28 \ V & - & - & 5 \\ drain cut-off current & V_{GS} = V_{GS(th)} + 3.75 \ V; & 16.75 & 19 & - \\ gate leakage current & V_{GS} = 11 \ V; \ V_{DS} = 0 \ V & - & - & 500 \\ forward transconductance & V_{DS} = 10 \ V; \ I_D = 3.57 \ A & - & 0.86 & - \\ drain-source on-state resistance & V_{GS} = V_{GS(th)} + 3.75 \ V; & - & 0.14 & - \\ \end{array} $

7. Test information

Remark: All testing performed in a class-AB production test circuit.

Table 7. Functional test information

Mode of operation: 1-carrier N-CDMA, single carrier IS-95 with pilot, paging, sync and 6 traffic channels (Walsh codes 8 - 13). PAR = 9.7 dB at 0.01 % probability on the CCDF, channel bandwidth is 1.2288 MHz; $f_1 = 2500$ MHz; $f_2 = 2700$ MHz; RF performance at $V_{DS} = 28$ V; $I_{Dq} = 1200$ mA; $T_{case} = 25$ °C; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$P_{L(AV)}$	average output power		-	30	-	W
Gp	power gain		14.8	16.5	-	dB
RL _{in}	input return loss		-	-10	-	dB
η_D	drain efficiency		22	26	-	%
ACPR _{885k}	adjacent channel power ratio (885 kHz)		-43	-47	-	dBc

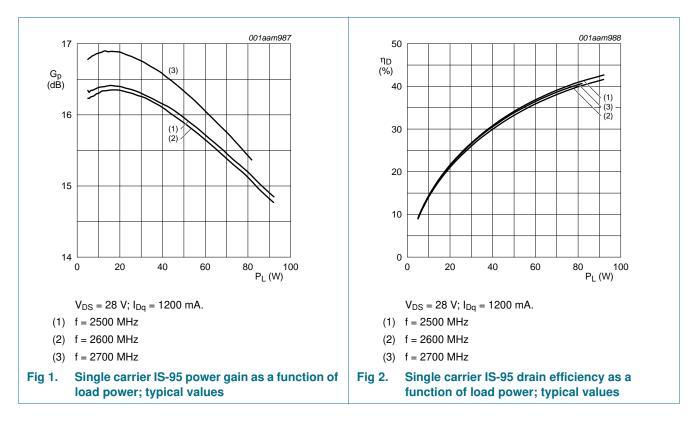
7.1 Ruggedness in class-AB operation

The BLF7G27L-150P and BLF7G27LS-150P are capable of withstanding a load mismatch corresponding to VSWR = 20 : 1 through all phases under the following conditions: $V_{DS} = 28 \text{ V}$; $I_{Dq} = 1200 \text{ mA}$; $P_L = 35 \text{ W}$ (IS-95); f = 2500 MHz.

BLF7G27L-150P_7G27LS-150P

7.2 Single carrier IS-95

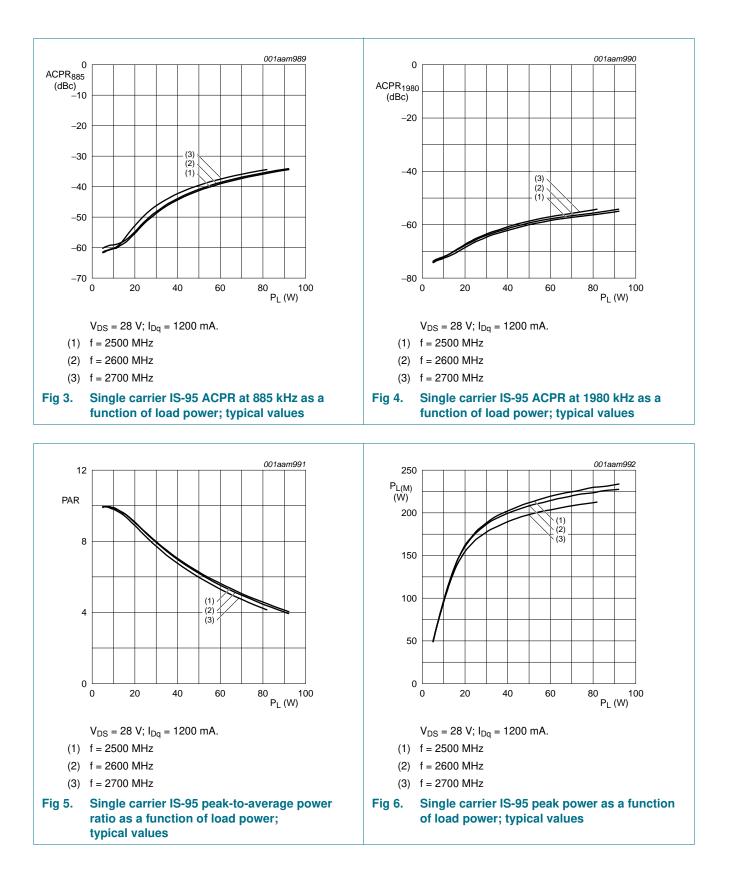
Single carrier IS-95 with pilot, paging, sync and 6 traffic channels (Walsh codes 8 - 13). PAR = 9.7 dB at 0.01 % probability on the CCDF. Channel bandwidth is 1.2288 MHz.



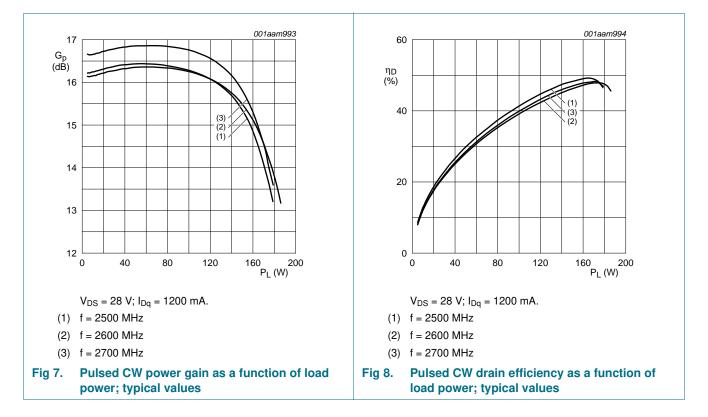
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BLF7G27L-150P; BLF7G27LS-150P

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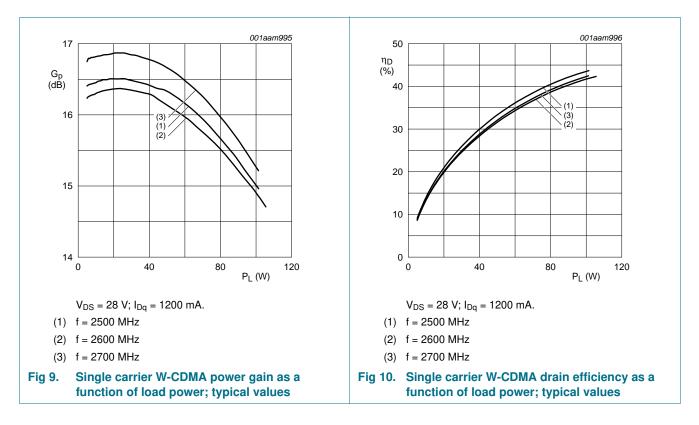


7.3 Pulsed CW

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7.4 Single carrier W-CDMA

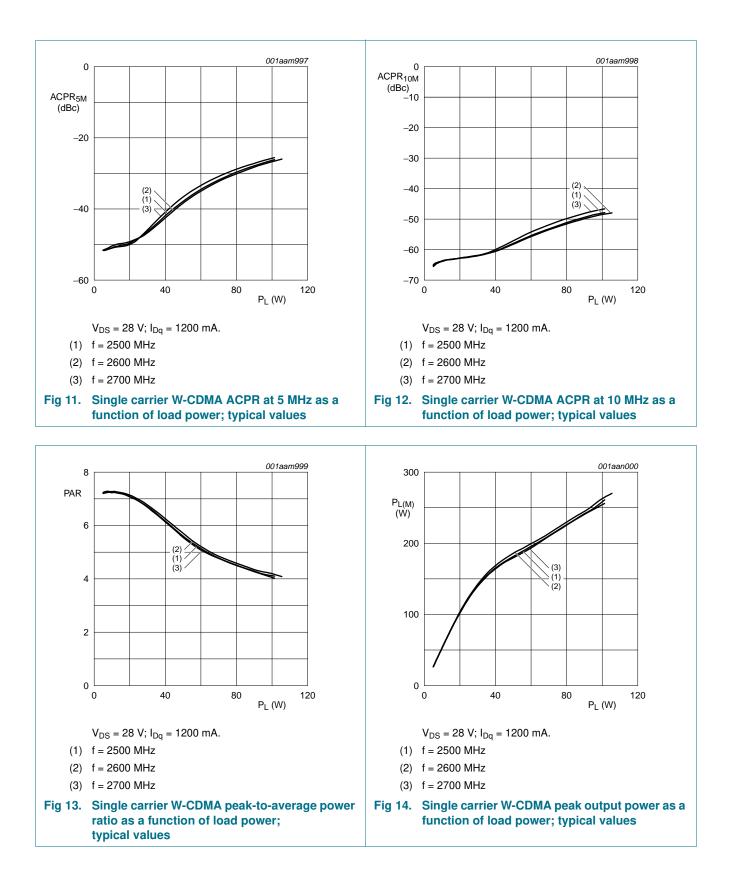
3GPP; test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF. Channel bandwidth is 3.84 MHz.



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BLF7G27L-150P; BLF7G27LS-150P

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8. Package outline

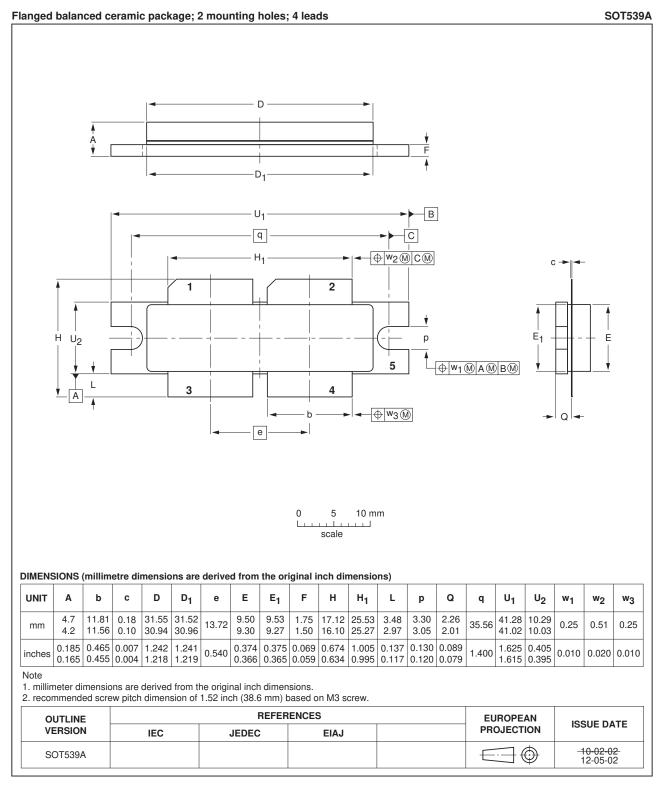


Fig 15. Package outline SOT539A

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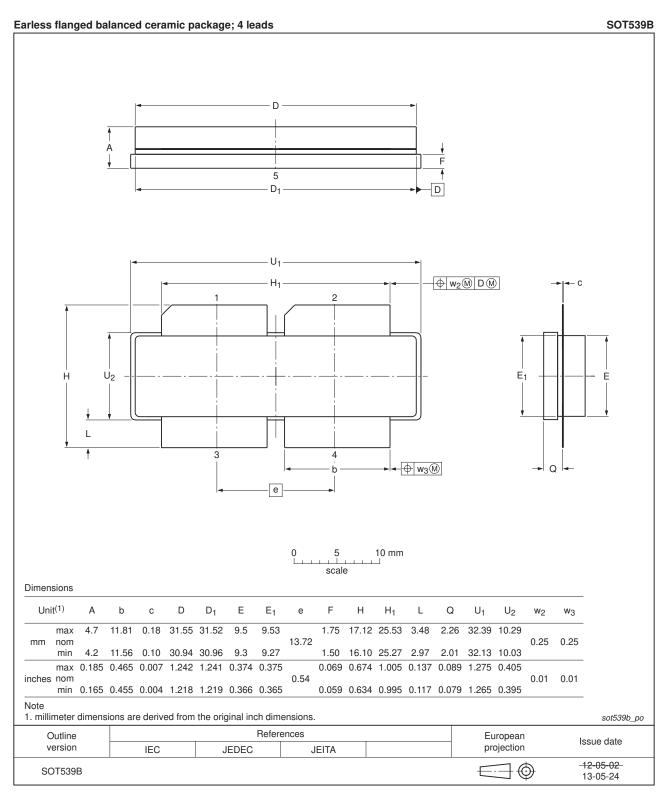


Fig 16. Package outline SOT539B

BLF7G27L-150P_7G27LS-150P Product data sheet

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9. Abbreviations

Table 8.	Abbreviations
Acronym	Description
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
IS-95	Interim Standard 95
ESD	ElectroStatic Discharge
LDMOS	Laterally Diffused Metal Oxide Semiconductor
LDMOST	Laterally Diffused Metal Oxide Semiconductor Transistor
N-CDMA	Narrowband Code Division Multiple Access
PAR	Peak-to-Average power Ratio
RF	Radio Frequency
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

10. Revision history

Table 9.Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF7G27L-150P_7G27LS-150P v.2	20130712	Product data sheet	-	BLF7G27L-150P_7G27LS-150P v.1
Modifications:	•	ackage outline <mark>Figure</mark> ation disclaimer adde		t.
BLF7G27L-150P_7G27LS-150P v.1	20101112	Product data sheet	-	-

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Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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